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Patent Number(s): WO2011111385-A1; JP2011191128-A

Title: Method for measuring terahertz waves in time domain, involves calibrating wave measuring apparatus by adjusting time intervals of measurement data to form time waveform on basis of comparison result

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Abstract: NOVELTY - The method involves measuring a time waveform of a terahertz wave related to a calibration sample (S202), where calibration spectrum shape of the sample is known by a terahertz wave measuring apparatus i.e. terahertz time-domain spectroscopy (THz-TDS) apparatus. A measurement spectrum is obtained (S203) by transforming the time waveform. The calibration spectrum and the measurement spectrum are compared (S205). The apparatus is calibrated by adjusting time intervals of measurement data to form the time waveform based on comparison result.

USE - Method for measuring terahertz waves in a time domain.

ADVANTAGE - The terahertz wave measuring apparatus is calibrated by adjusting time intervals of the measurement data to form the time waveform on the basis of results of the comparison, so that the calibration spectrum is calibrated to improve quantity of spectrum information to be output from the apparatus.

DETAILED DESCRIPTION - An INDEPENDENT CLAIM is also included for a terahertz wave measuring apparatus comprising a generation unit.

DESCRIPTION OF DRAWING(S) - The drawing shows a flowchart illustrating operation of a measuring apparatus and a measurement method.

Step for measuring time waveform (S202)

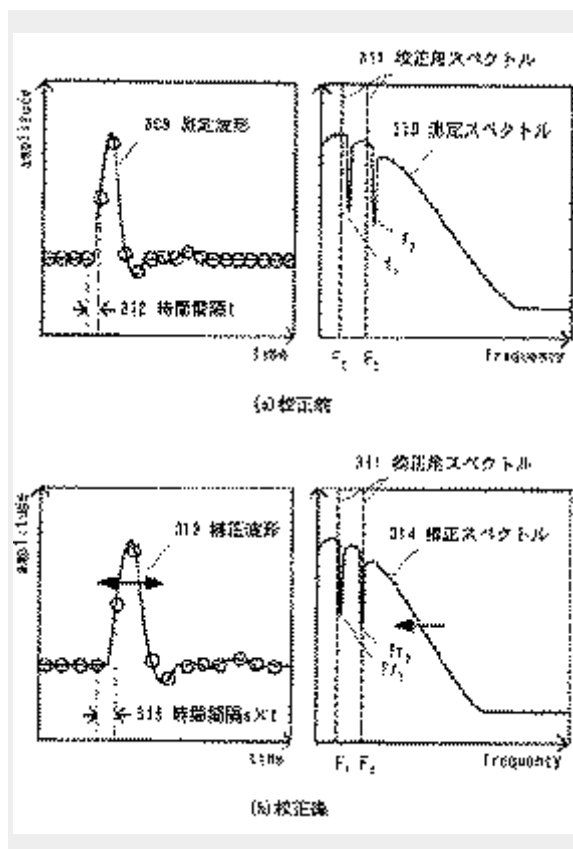
Step for obtaining measurement spectrum (S203)

Step for selecting spectra (S204)

Step for comparing calibration spectrum and measurement spectrum (S205)

Step for obtaining corrected spectrum (S208)

Drawing:



Derwent Class Code(s): S03 (Scientific Instrumentation, photometry, calorimetry)

Derwent Manual Code(s): S03-A02B; S03-A05; S03-E04A5

IPC: G01J-003/42; G01N-021/35; G01N-021/27

Patent Details:

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(National): AE; AG; AL; AM; AO; AT; AU; AZ; BA; BB; BG; BH; BR; BW; BY; BZ; CA; CH; CL; CN; CO; CR; CU; CZ; DE; DK; DM; DO; DZ; EC; EE; EG; ES; FI; GB; GD; GE; GH; GM; GT; HN; HR; HU; ID; IL; IN; IS; KE; KG; KM; KN; KP; KR; KZ; LA; LC; LK; LR; LS; LT; LU; LY; MA; MD; ME; MG; MK; MN; MW; MX; MY; MZ; NA; NG; NI; NO; NZ; OM; PE; PG; PH; PL; PT; RO; RS; RU; SC; SD; SE; SG; SK; SL; SM; ST; SV; SY; TH; TJ; TM; TN; TR; TT; TZ; UA; UG; US; UZ; VC; VN; ZA; ZM; ZW

Cited Patent(s):

WO2011111385-A1	JP2007101370-A	TOCHIGI NIKON KK (TOCH-Non-standard); NIKON CORP (NIKR)	FUKUSHIMA K
	US2009198466-A1	CANON KK (CANO)	KAJIKI K; OUCHI T
	US2009302223-A1	SONY CORP (SONY)	ITO K; TAMADA S